

Freeform Search

Database:
 US Pre-Grant Publication Full-Text Database
 US Patents Full-Text Database
 US OCR Full-Text Database
 EPO Abstracts Database
 JPO Abstracts Database
 Derwent World Patents Index
 IBM Technical Disclosure Bulletins

Term: L2 and (bug or error or defect).ab.

Display: 50 Documents in **Display Format:** REV Starting with Number 1

Generate: ☐ Hit List ☒ Hit Count ☐ Side by Side ☐ Image

Search

Clear

Interrupt

Search History

DATE: Monday, February 19, 2007 [Purge Queries](#) [Printable Copy](#) [Create Case](#)

<u>Set</u> <u>Name</u> <u>Query</u> side by side	<u>Hit</u> <u>Count</u>	<u>Set</u> <u>Name</u> result set
<i>DB=USPT; PLUR=NO; OP=OR</i>		
<u>L6</u> L2 and (bug or error or defect).ab.	3	<u>L6</u>
<u>L5</u> L2 and ratio	16	<u>L5</u>
<u>L4</u> L2 and ((defect or bug) ADJ list)	1	<u>L4</u>
<u>L3</u> L2 and (defect or bug)	13	<u>L3</u>
<u>L2</u> L1 and 717/101.ccls.	81	<u>L2</u>
<u>L1</u> (estimating and (software aDJ project) and defects and (team or group or task) and backlog or (back ADJ log) or ((defect ADJ backlog) or (bug ADJ list) or (backlog or list)))	187823	<u>L1</u>

END OF SEARCH HISTORY